Search Notes



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Applicant(s)/Patent Under Reexamination

MAYER ET AL.

Examiner

EVAN H LANGDON

Art Unit

3654

SEARCHED

Class	Subclass	Date	Examiner
226	95,97.3	8/11/2008	/EL/
242	615.11,615.12,615.21	8/11/2008	/EL/

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INTERFERENCE SEARCH

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